

INSTRUMENT FACILITIES AVAILABLE AT THE INDIVIDUAL SAIFs

Sophisticated Analytical Instrument Facility, AIIMS, New Delhi

| Sl. No. | Instrument | Make/ Model | Major Specifications/ Accessories available | Type of measurement/analysis available |
|-------------------|----------------------------------|---------------------------|---|---|
| 1. | Scanning Electron Microscope | LEO 435 VP | Acc. voltage: 30 kV; Magnification: upto 3,00,000x; Image analyzer system | SEM study as above with low vacuum and image analysis facility. |
| 2. | Transmission Electron Microscope | Philips CM 10 | Acc. voltage: 100 kV; Magnification: upto 4,50,000x; Cryo-attachment | Study of the internal architecture of cells and tissues for research, diagnostic and teaching purposes. |
| 3. | Transmission Electron Microscope | FEI Philips Morgagni 268D | Acc. voltage: 100 kV Magnification: upto 2,80,000x | TEM study as above with image analysis facility. |
| 4. | SEM Specimen preparation | | | |
| | a. Critical Point Dryer | Jumbo | | Drying of biological samples. |
| | b. Sputter coater | SCD 020 | | Metal coating of biological samples. |
| 5. | TEM Specimen preparation | | | |
| | 1. a.Ultramicrotome | Ultracut E | | Ultrathin sectioning of biological samples by conventional technique & Cryotechnique. |
| | 1. b.Ultramicrotome | Ultracut UCT | | |
| c. Microwave oven | Pelco | | Quick method of TEM sample processing and staining mainly used for diagnostic purposes. | |